

New Applications Enabled by Complex 3D Microsystems



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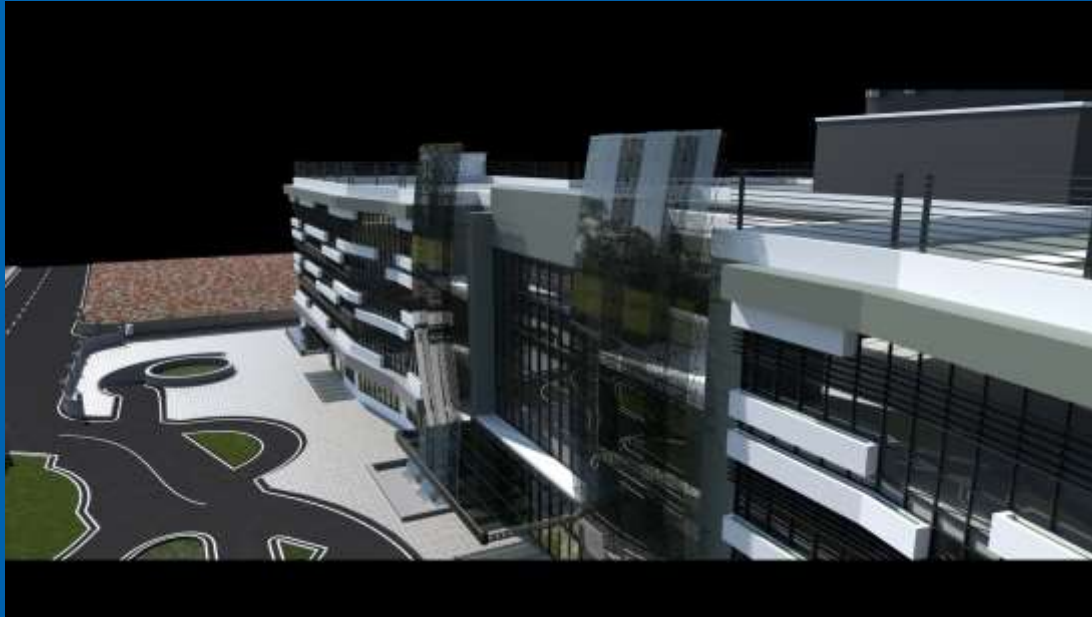
Josh Fryman, PhD
Office of the CTO, Intel Fellow
Aug 22, 2023

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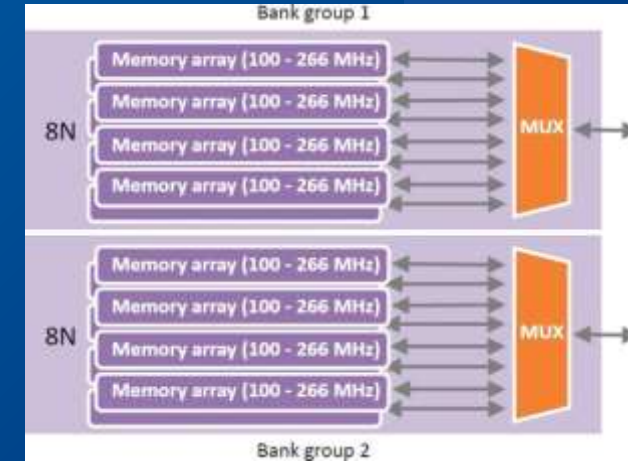


ELECTRONICS
RESURGENCE
INITIATIVE 2.0

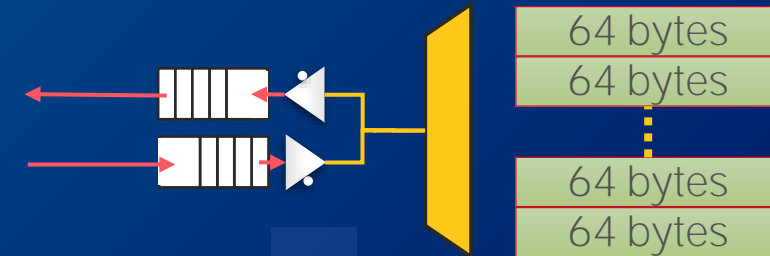
Let's talk about memory for a moment ...



The real world is 3D (or higher)

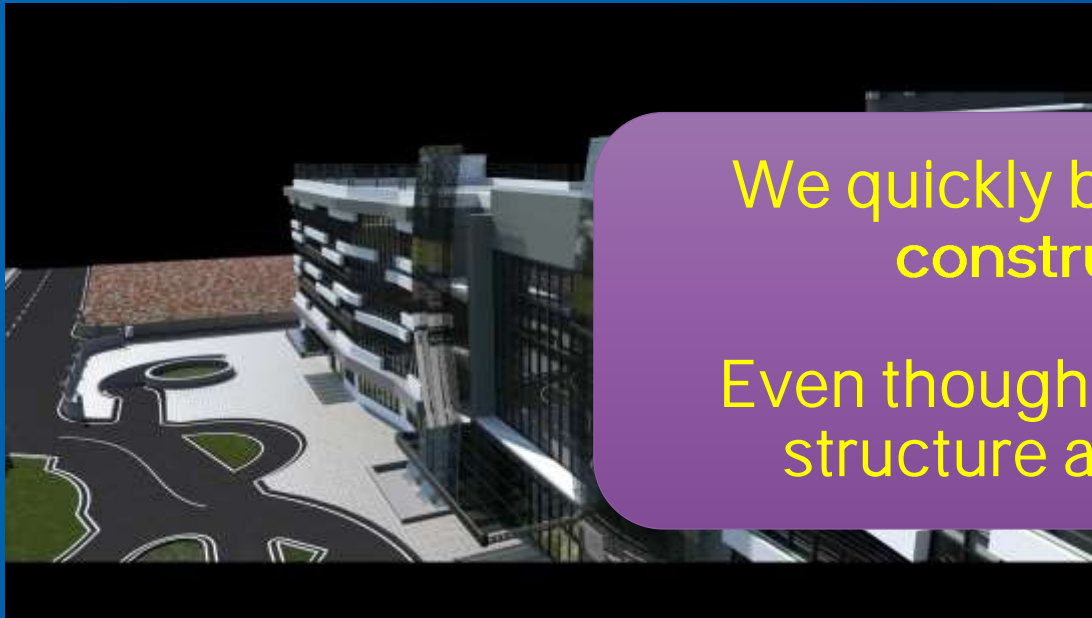


Memory is 2D internally



Which we make look 1D

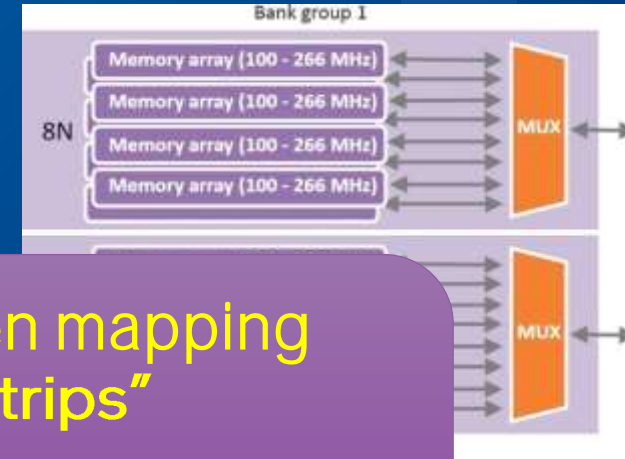
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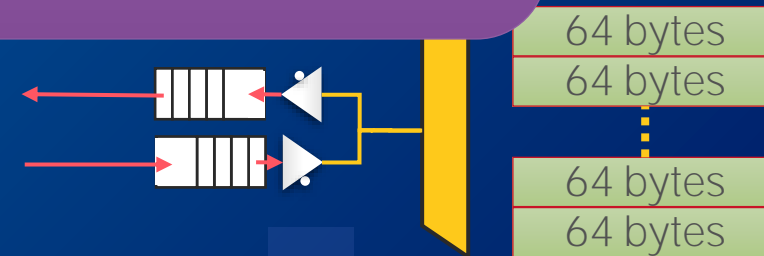
The real world is 3D (or higher)

We quickly bottleneck when mapping constructs onto 1D "strips"

Even though it has a multi-dimensional structure and potential to do more

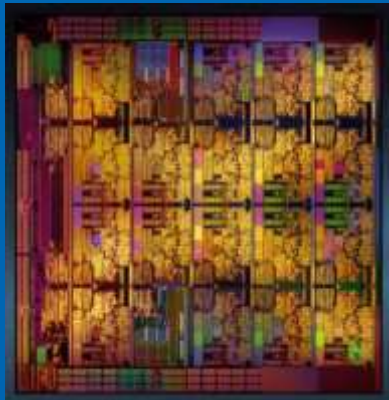


Externally

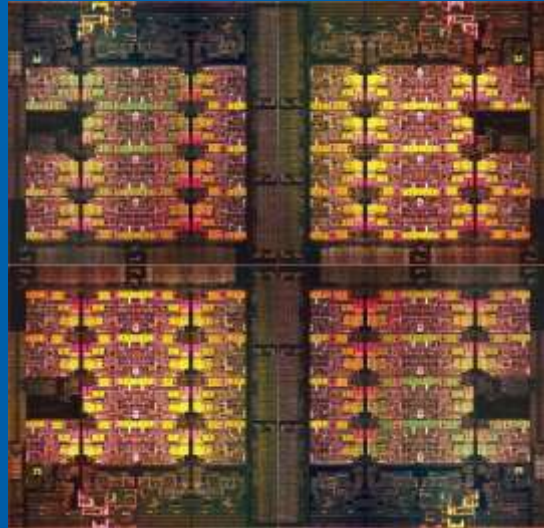


Which we make look 1D

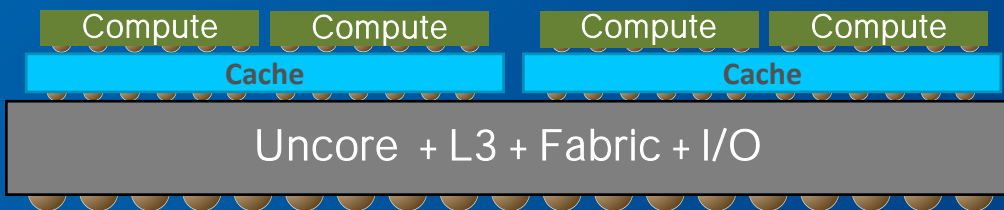
Chip design: are we 3D today?



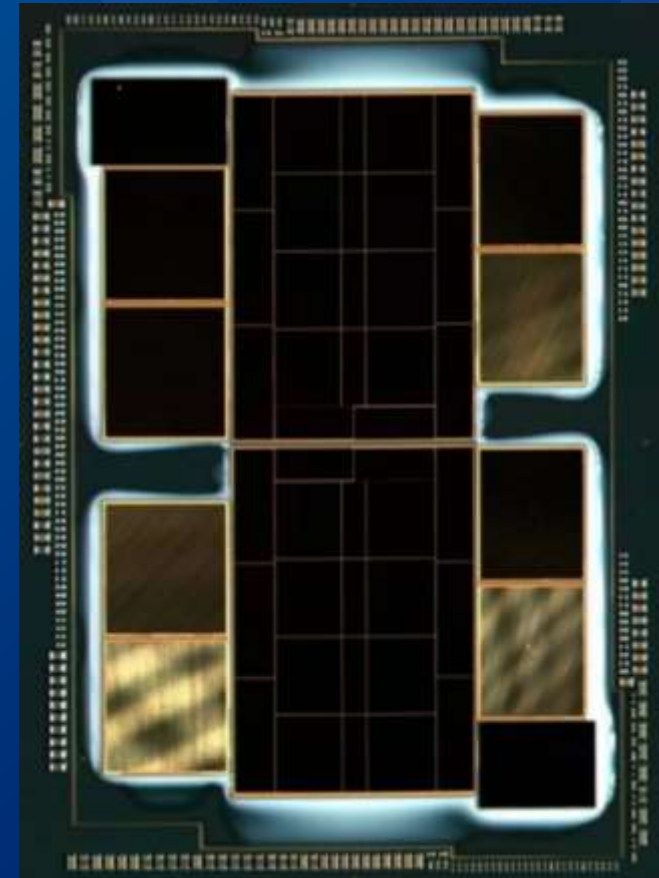
Monolithic



Polyolithic
multi-chip

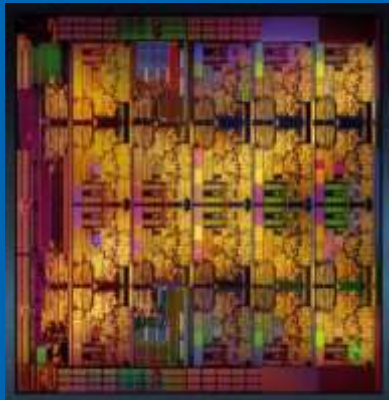


Polyolithic tiled

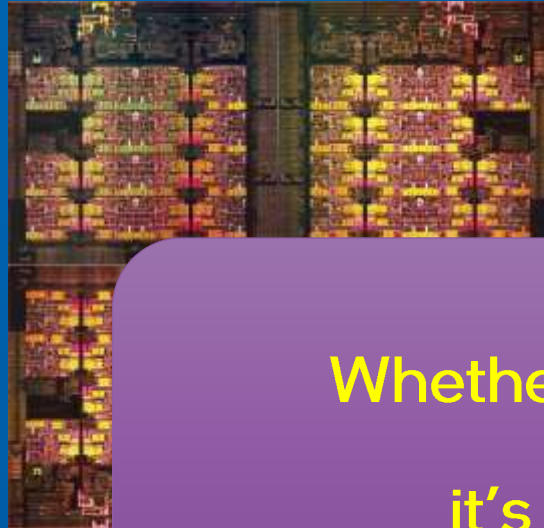


Heterogenous
tiled multi-chip

Chip design: are we 3D today?



Monolithic



Multi-chip

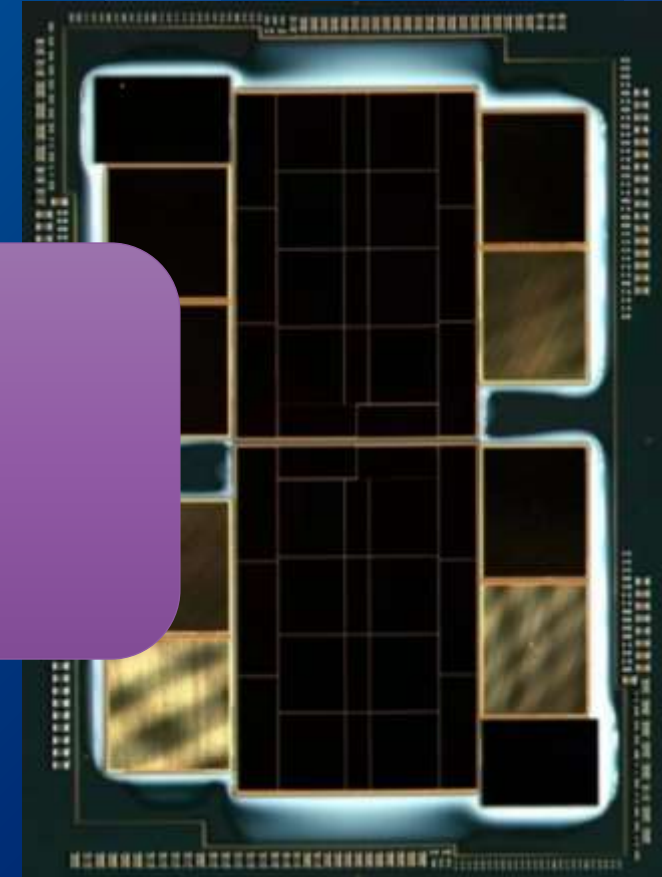
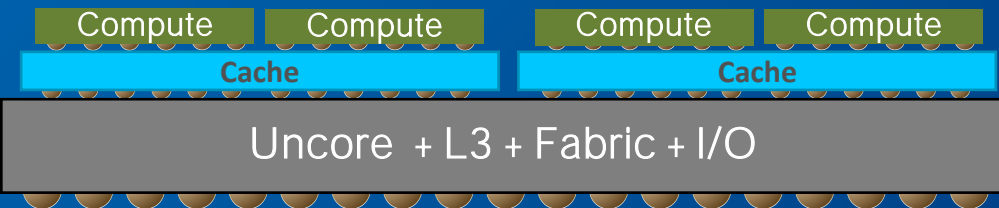


I/O Tile



I/O Tile

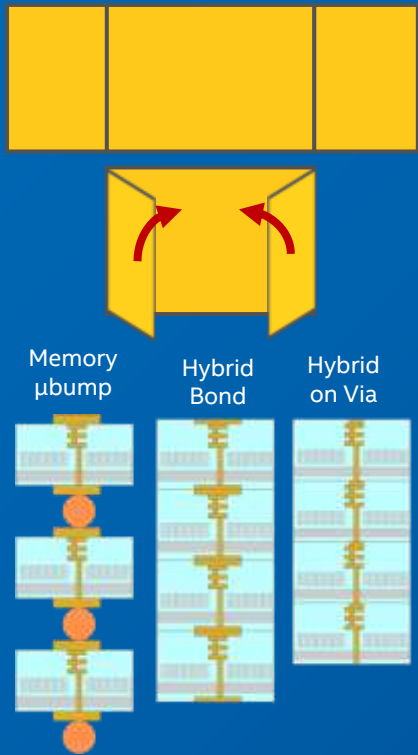
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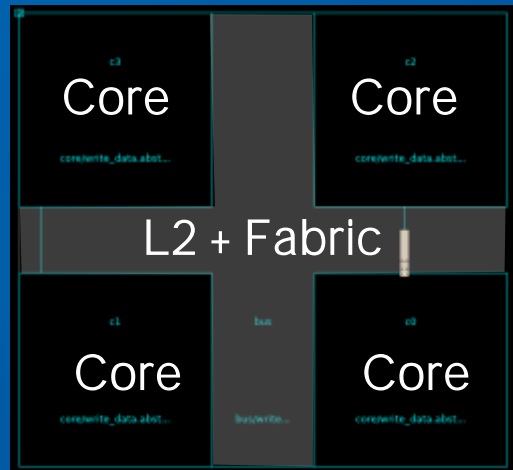
Heterogenous tiled multi-chip

Whether it's 2.5D or 3D in name,
it's just "planar thinking"

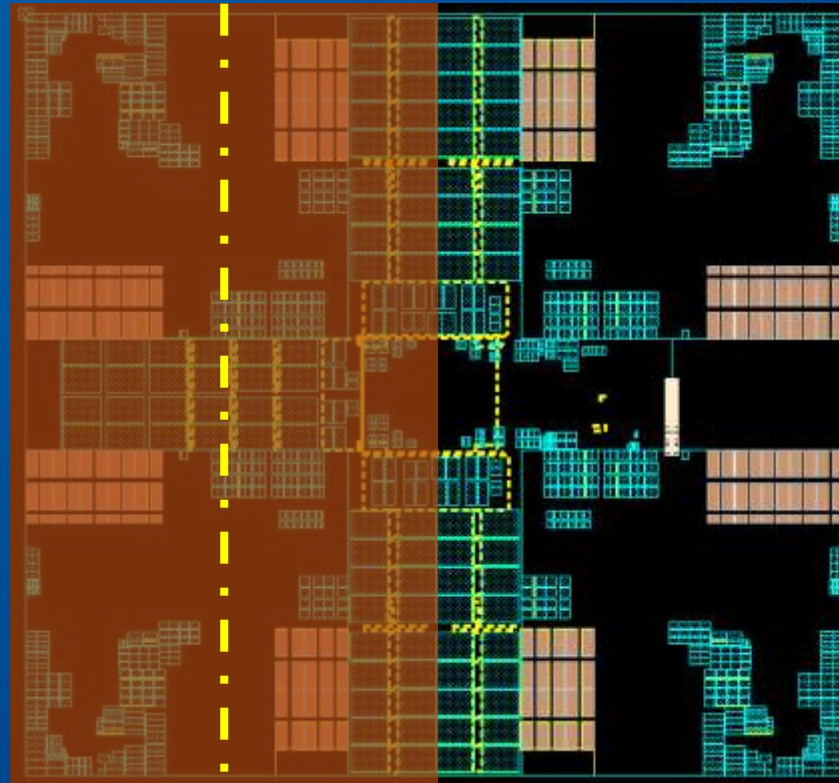
What about cutting-edge 3D?



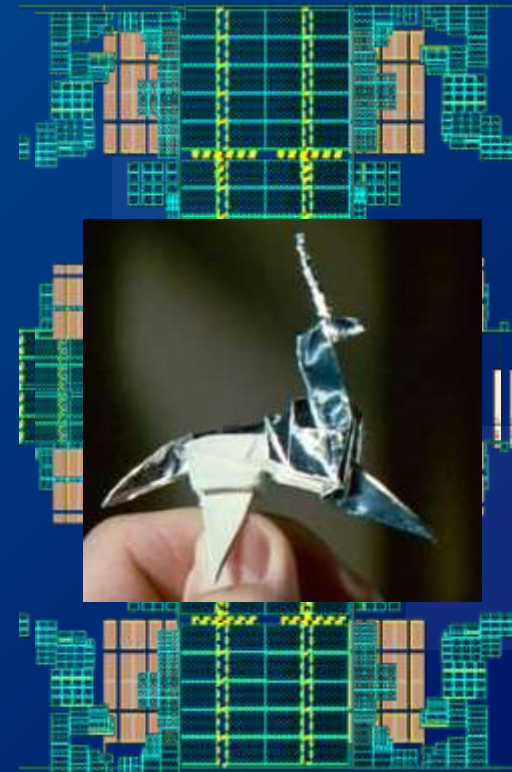
Core Folding



4-Core Tile Floorplan

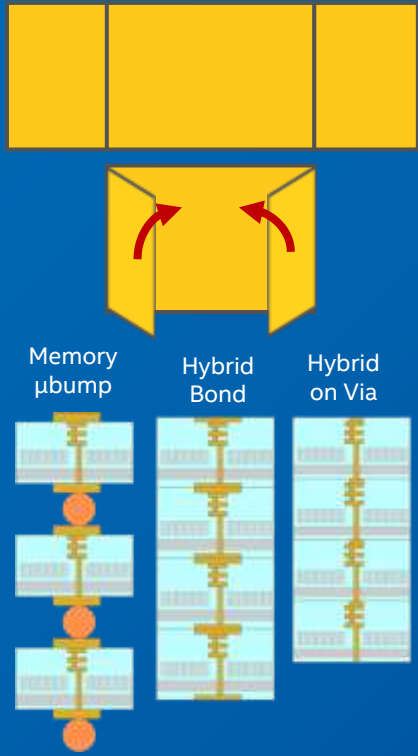


Fold Line Concept with Hybrid Bonding

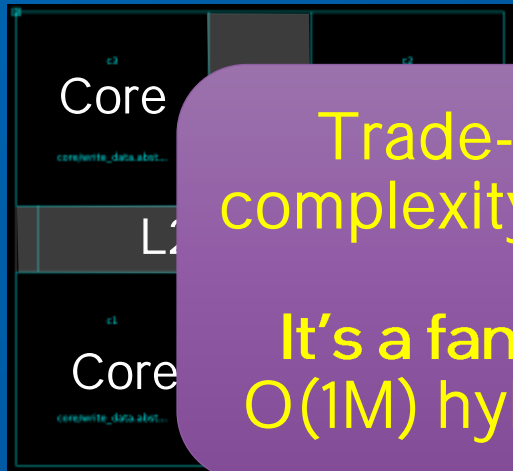


"Shrink"

What about cutting-edge 3D?



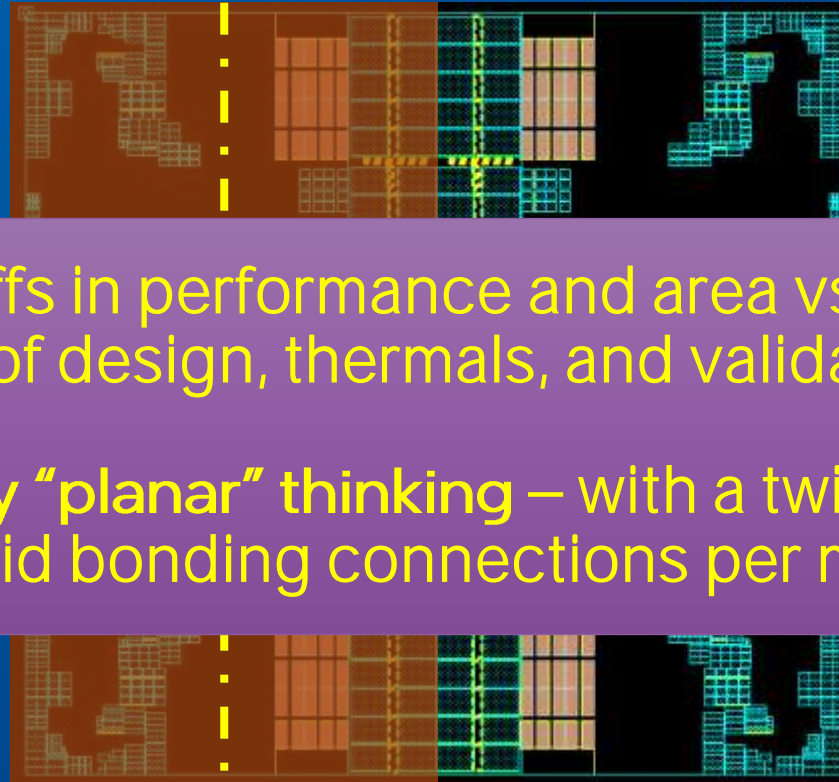
Core Folding



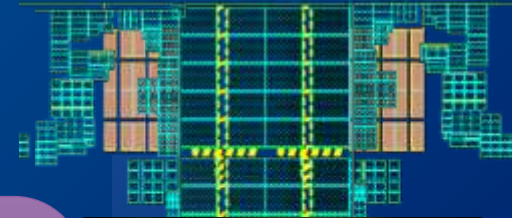
4-Core Tile Floorplan

Trade-offs in performance and area vs. complexity of design, thermals, and validation

It's a fancy "planar" thinking – with a twist: $O(1M)$ hybrid bonding connections per mm^2



Fold Line Concept with Hybrid Bonding

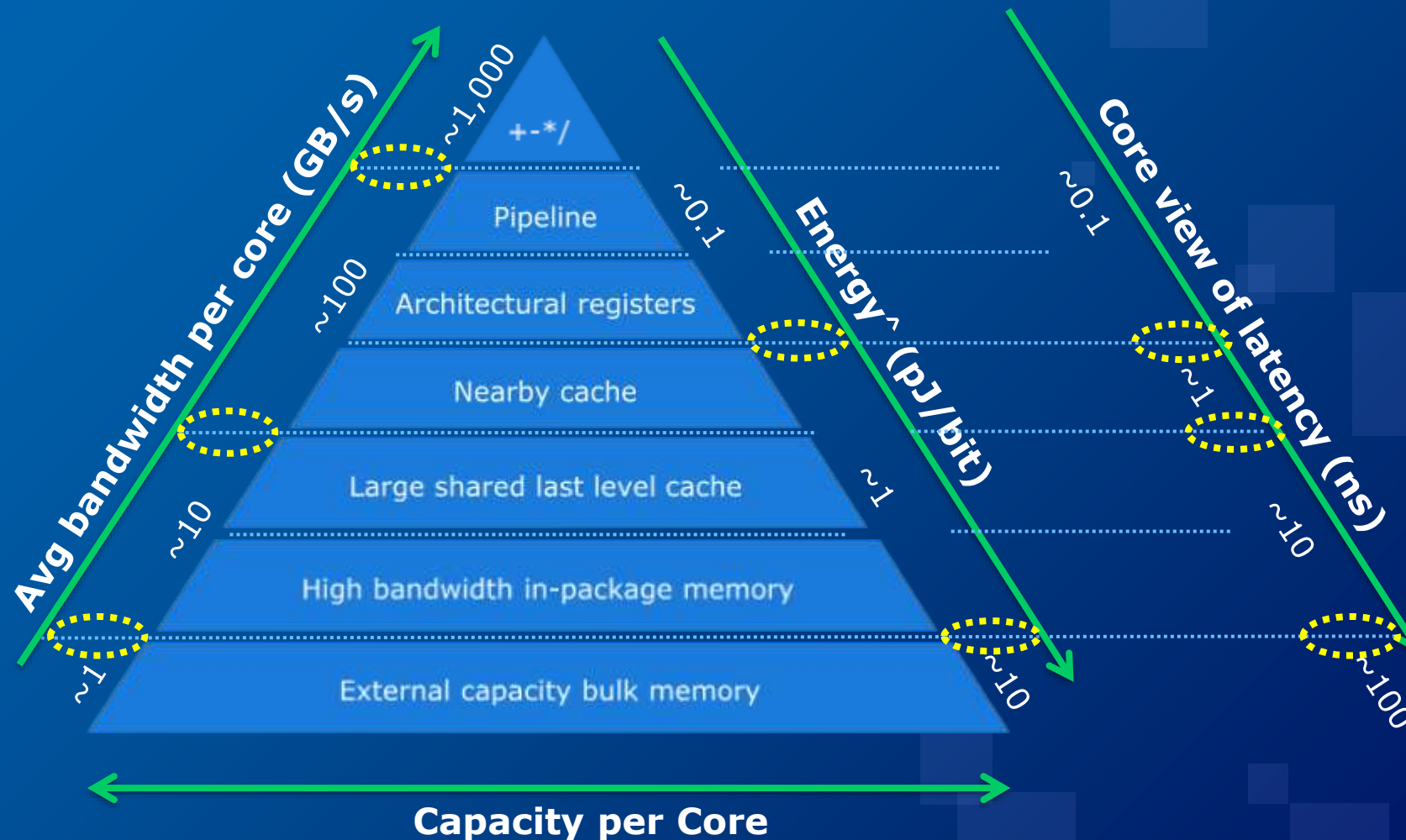


"Shrink"



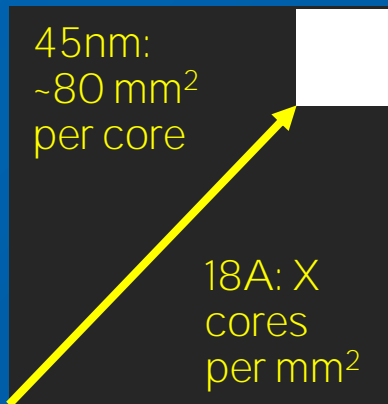
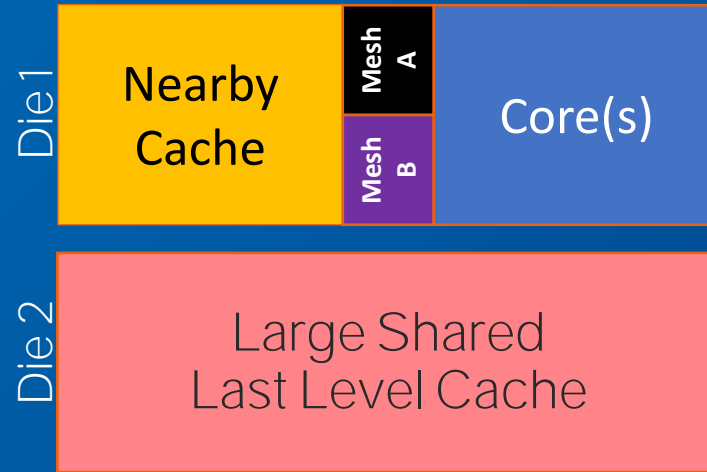
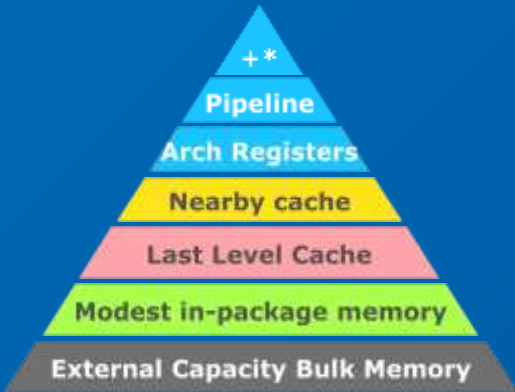
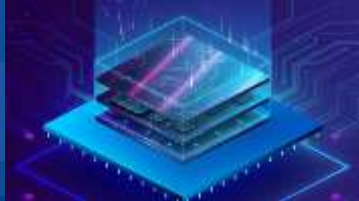
But are we exploiting the right things?

Tapering divisions in bandwidth, energy, and latency are opportunities to optimize

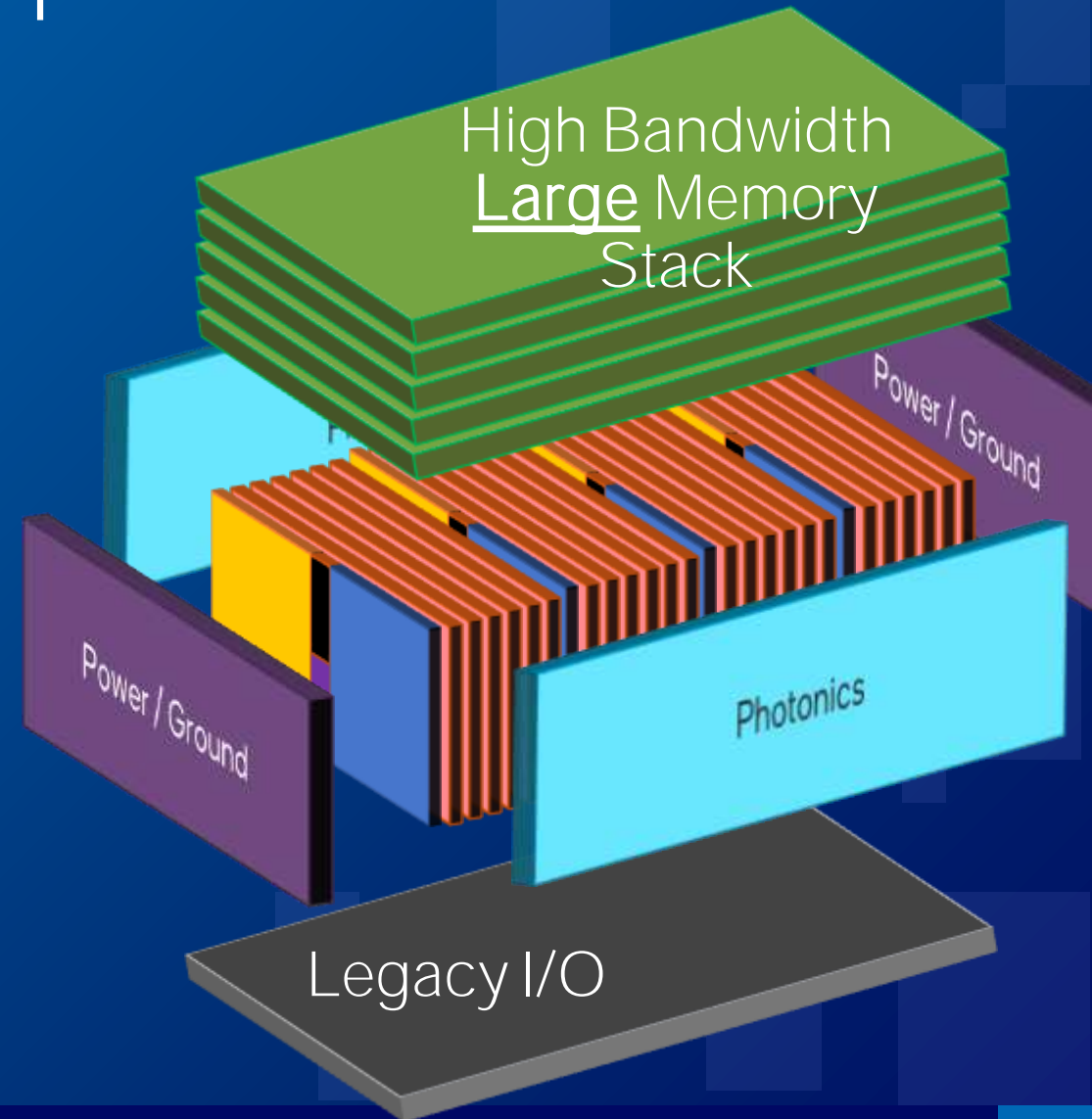
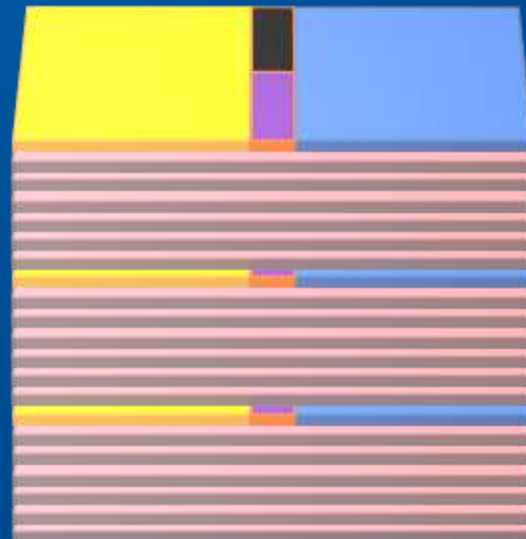


^Not counting overheads for access

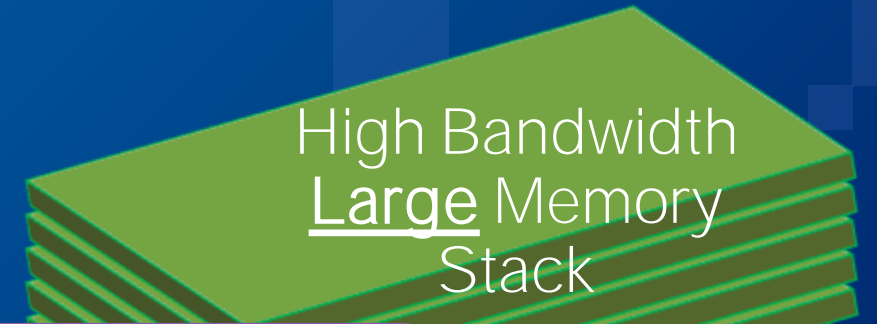
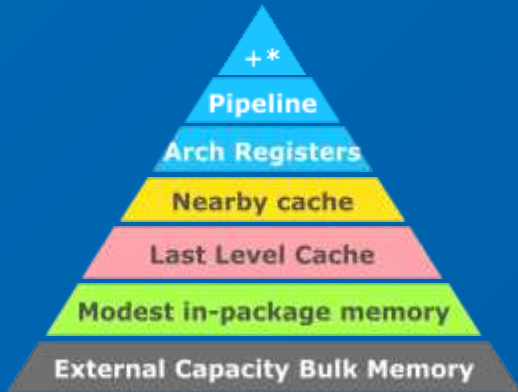
3D as a spatial concept, not planar



Fab Shrink

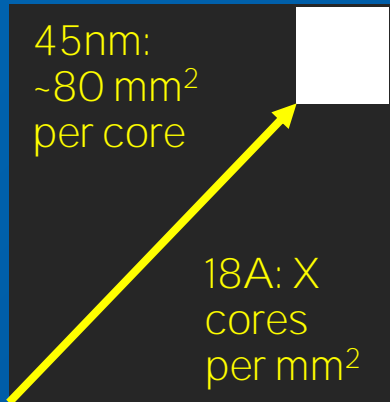


3D as a spatial concept, not planar

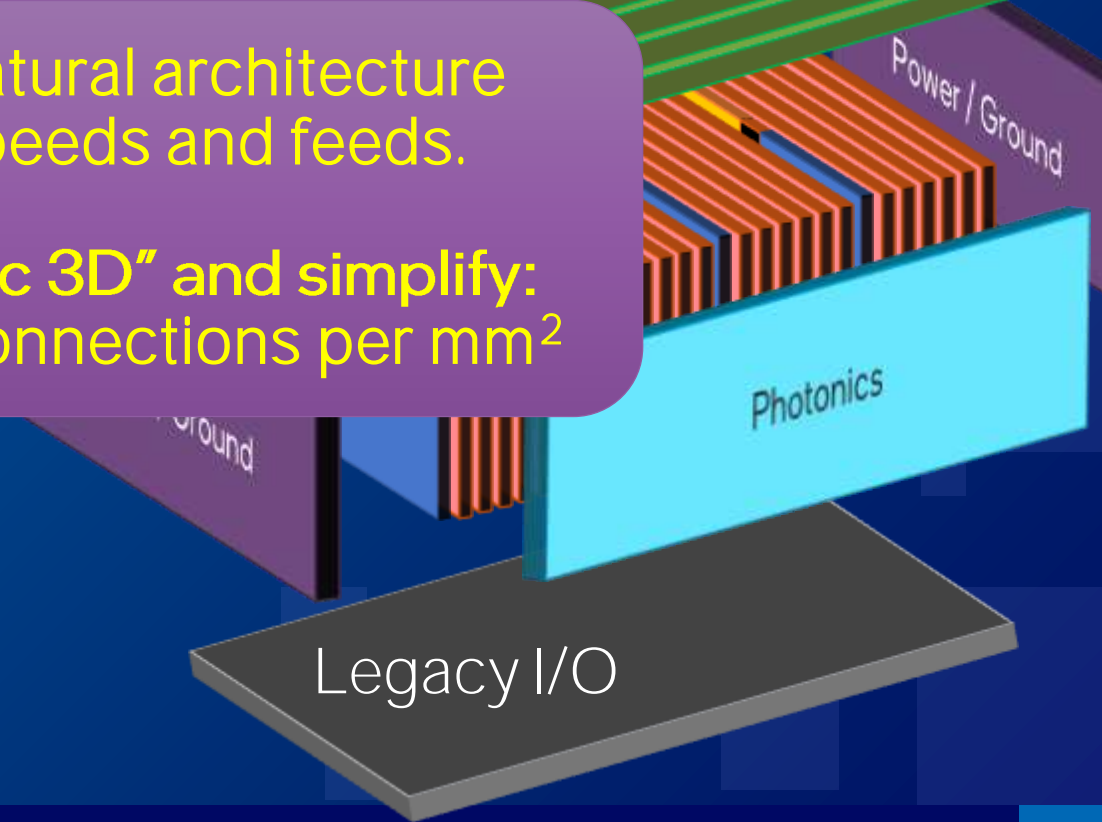
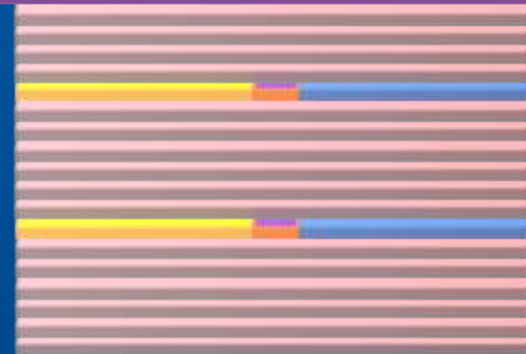


Match trade-offs to natural architecture inflection points – speeds and feeds.

Use all 6 faces of “cubic 3D” and simplify:
O(1k) hybrid bonding connections per mm²



Fab Shrink



Application breakthroughs of dense 3DHI



Aurora 2.0 ExaFLOP System

- 1 Rack $\approx 9.8 \text{ m}^3$
 - 128 Xeons + 384 Xe + Slingshot fabric
- Fits in 3D cube at 40 mm per side
 - $>100,000\times$ smaller volume



Apple's VisionPro AR Headset

- Multiple types of silicon, packages
 - Size, weight, and power are limiters
- Rice $\approx 2 \text{ mm} \times 2.75 \text{ mm} \times 6 \text{ mm}$ per grain [1]
 - Fits Apple silicon and $\sim 0.5 \text{ TB}$ memory

[1] <https://www.ncbi.nlm.nih.gov/pmc/articles/PMC6145214>

Challenges to achieving dense 3D

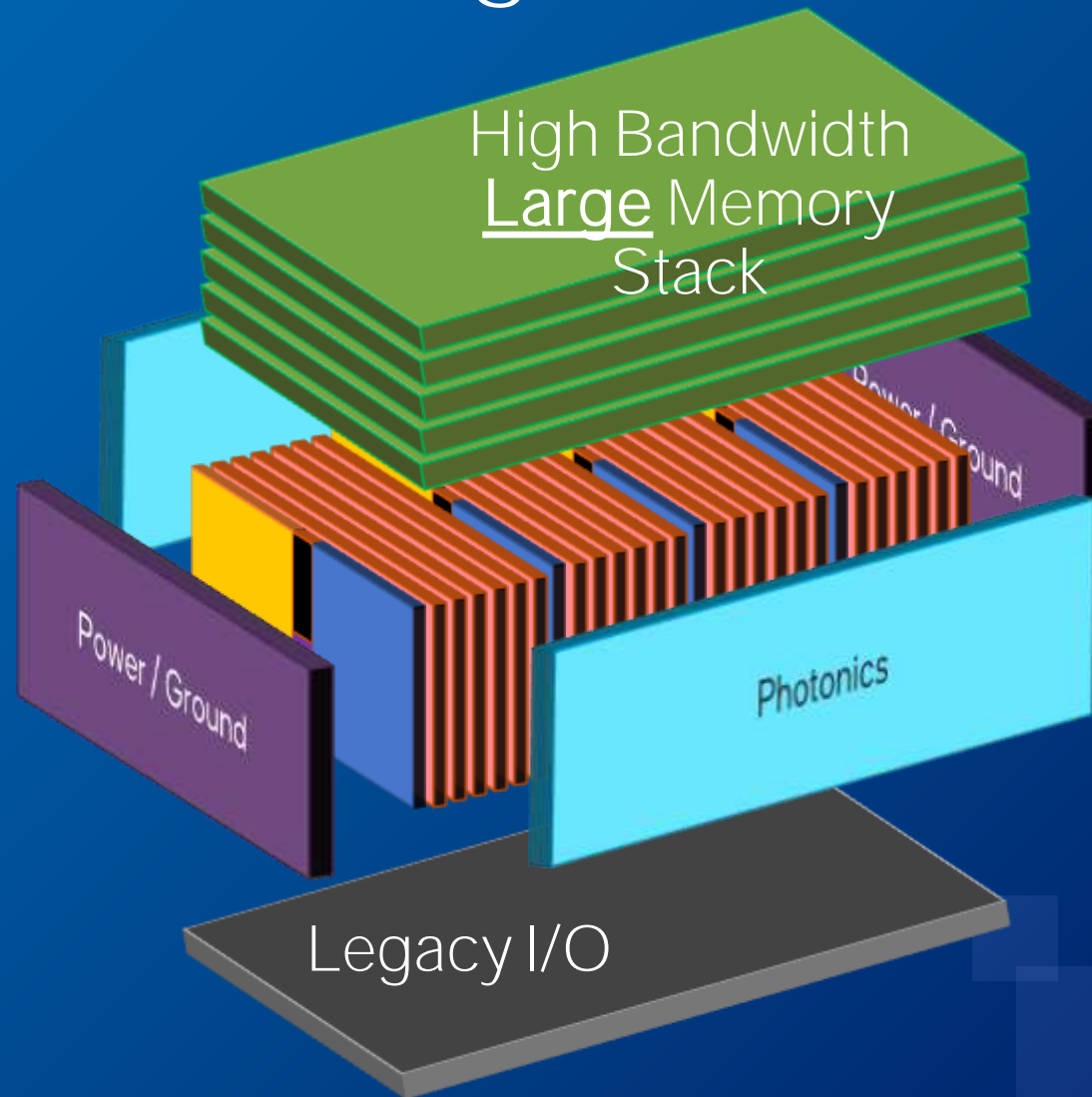


Manufacturing:

- edge polish
- right-angle attach
- via density
- bonding speed
- rework support
- redundancy
- tooling Z-height
- wafer thinning

Power and Thermals:

- thermal density
- power delivery
- cooling layers
- heterogeneous material



EDA:

- rotated die
- taper point isolation
- non-planar libraries
- formal verification
- DF<all> 1,000 layers
- scan chain time
- tests and coverage

Design:

- graceful degradation
- extreme interop
- built-in redundancy
- pluggable modules
- abstractions for all

Challenges to achieving dense 3D



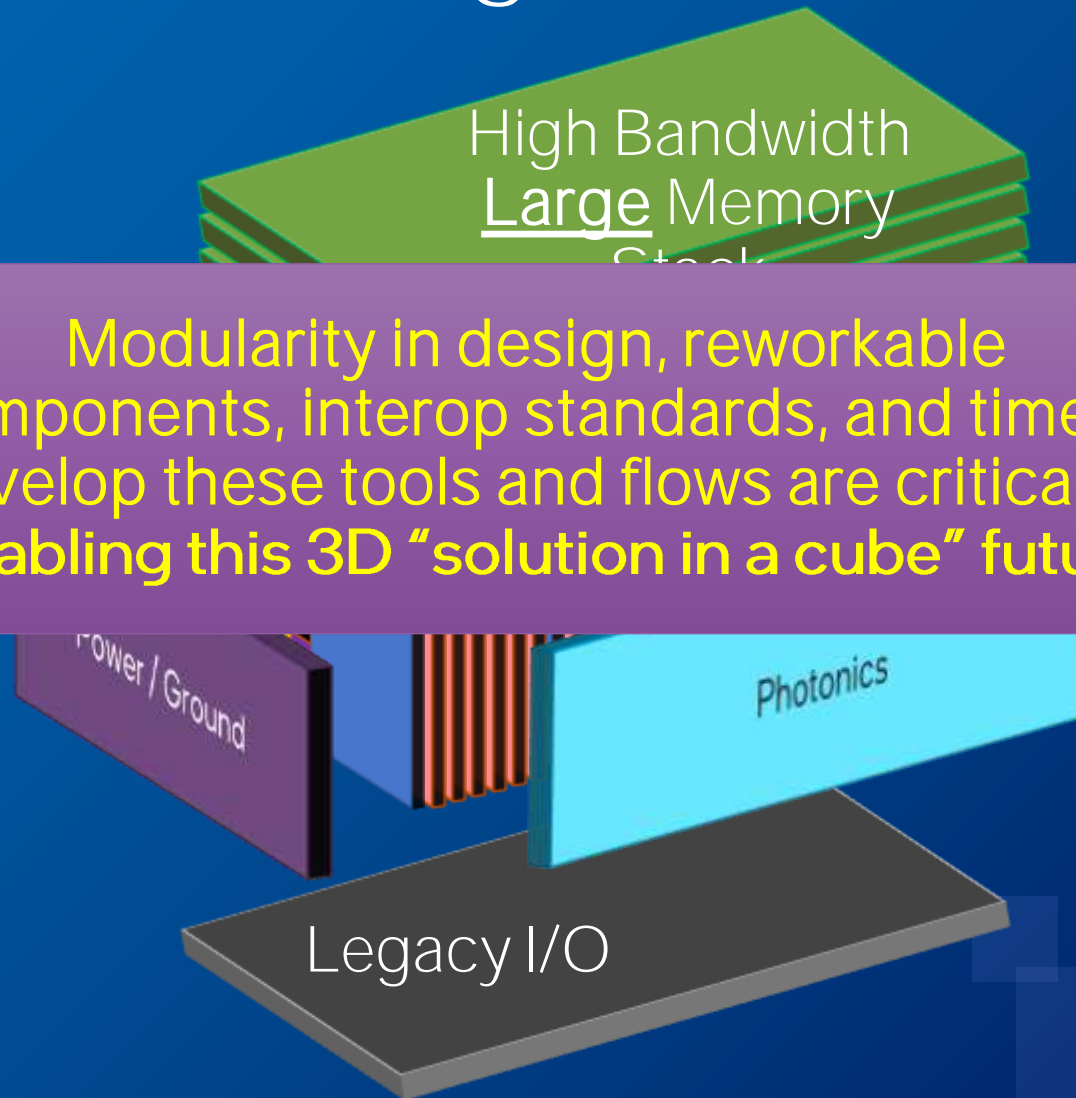
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Modularity in design, reworkable components, interop standards, and time to develop these tools and flows are critical to enabling this 3D “solution in a cube” future

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The image features the Intel logo centered on a solid blue background. The logo consists of the word "intel" in a white, lowercase, sans-serif font. A small, light blue square is positioned above the letter "i". To the right of the word "intel" is a registered trademark symbol (®). The background is decorated with a grid of squares of varying sizes and shades of blue, creating a subtle pattern.

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